

FAST 74F27 Gate

Triple 3-Input NOR Gate

FAST Products

Product Specification

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F27	3.0ns	6.5mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$; $T_A = 0^\circ C$ to $+70^\circ C$
14-Pin Plastic DIP	N74F27N
14-Pin Plastic SO	N74F27D

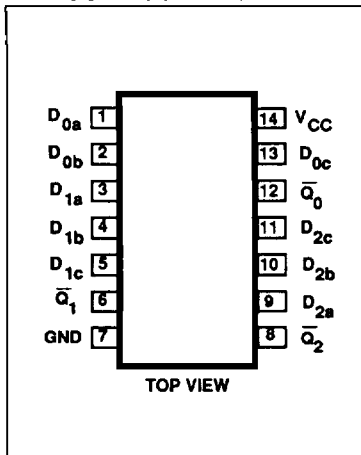
INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D_{na} , D_{nb} , D_{nc}	Data inputs	1.0/1.0	$20\mu A/0.6mA$
\bar{Q}_n	Data output	50/33	$1.0mA/20mA$

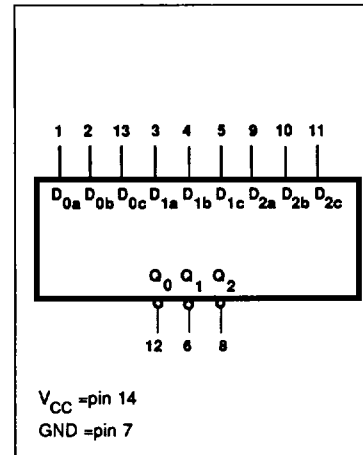
NOTE:

1. One (1.0) FAST Unit Load is defined as: $20\mu A$ in the High state and $0.6mA$ in the Low state.

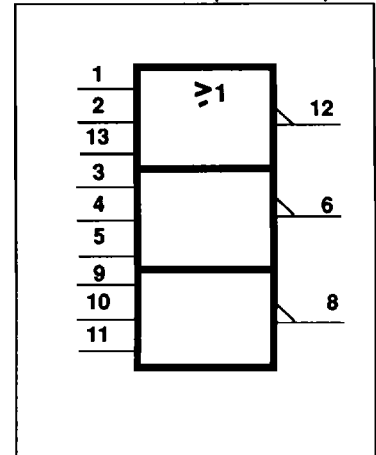
PIN CONFIGURATION



LOGIC SYMBOL



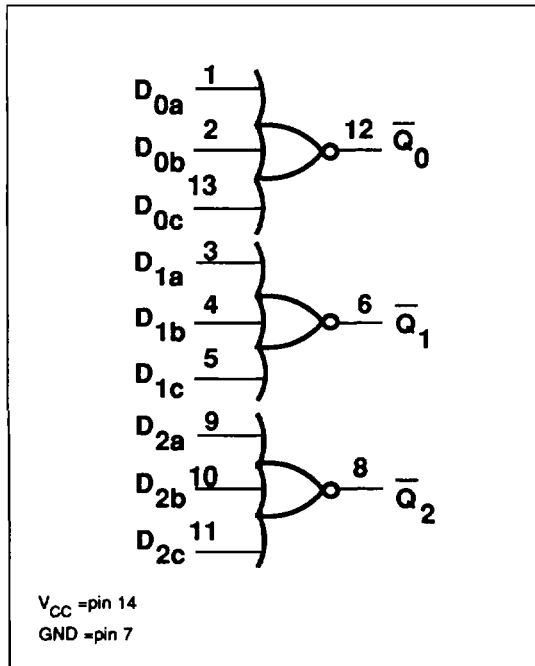
LOGIC SYMBOL (IEEE/IEC)



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74F27

LOGIC DIAGRAM



FUNCTION TABLE

INPUTS			OUTPUTS
D_{na}	D_{nb}	D_{nc}	\bar{Q}_n
L	L	L	H
X	X	H	L
X	H	X	L
H	X	X	L

H = High voltage level
L = Low voltage level
X = Don't care

ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to $+V_{CC}$	V
I_{OUT}	Current applied to output in Low output state	40	mA
T_A	Operating free-air temperature range	0 to +70	°C
T_{STG}	Storage temperature	-65 to +150	°C

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74F27

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-1	mA
I_{OL}	Low-level output current			20	mA
T_A	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT	
			Min	Typ ²	Max		
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$	$\pm 10\%V_{CC}$	2.5		V	
		$V_{IH} = \text{MIN}, I_{OH} = \text{MAX}$	$\pm 5\%V_{CC}$	2.7	3.4	V	
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.30	0.50	V
		$V_{IH} = \text{MIN}, I_{OL} = \text{MAX}$	$\pm 5\%V_{CC}$		0.30	0.50	V
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$		-0.73	-1.2	V	
I_I	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 7.0\text{V}$			100	μA	
I_{IH}	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$			20	μA	
I_{IL}	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$			-0.6	mA	
I_{OS}	Short-circuit output current ³	$V_{CC} = \text{MAX}$		-60	-150	mA	
I_{CC}	Supply current (total)	I_{CCH}	$V_{CC} = \text{MAX}$	$V_{IN} = \text{GND}$	4.0	5.5	mA
		I_{CCL}		$V_{IN} = 4.5\text{V}$	8.5	12.0	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

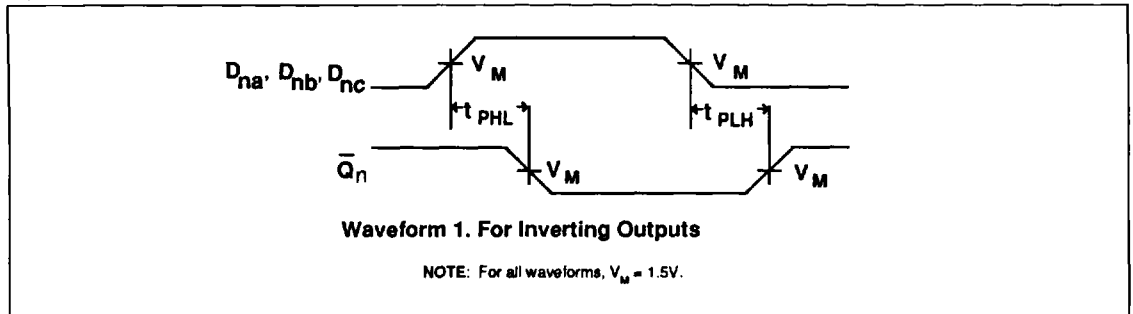
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74F27

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation delay D_{na}, D_{nb}, D_{nc} to \bar{Q}_n	Waveform 1	2.0 1.0	3.5 2.5	5.0 4.5	1.5 1.0	5.5 4.5	ns

AC WAVEFORMS



TEST CIRCUIT AND WAVEFORMS

